FORM PTO-144	9 U.S. DEPARTN	IENT OF	COMMERCE
(Modified)	PATENT AND T	RADEMA	RK OFFICE

## INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(Use several sheets if necessary)

ATTY, DOCKET NO. 5740.02	SERIAL NO			
APPLICANT: NEUHAUS et al.				
FILING DATE Murch 19, 2001	GROUP 2000			

AUG 0 3 2001

#### U.S. PATENT DOCUMENTS

XAMINER INITIAL		PATENT NUMBER	ISSUE DATE	PATENTEE	CLASS	SUBCLASS	FILING DATE II APPROPRIATE
Rul	A	4814040	03/21/89	OZAWA	156	634	
PN pm	В	5128746	07/07/92	PENNISFet al.	357	72	
							79
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#### FOREIGN PATENT OR PUBLISHED FOREIGN PATENT APPLICATION

DOCUMENT PUBLIS		PUBLISHED				TRANSLA	TRANSLATION	
	NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	YES	NO	
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 $OTHER\ DOCUMENTS\ (Including\ Author,\ Title,\ Date,\ Pertinent\ Pages,\ Etc.)$ 

EXAMINER accident	DATE CONSIDERED // 28/ )
EXAMINER: Initial if citation considered, whether or not citation is in conformance	e with MPEP 609; Draw line through citation if not in conformance
and not considered. Include copy of this form with next communication to applicant	•

FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE (Modified) PATENT AND TRADEMARK OFFICE	ATTY, DOCKET NO. 5740.02	SERIAL NO. 09/812,140
(Modified) PATENT AND TRADEMARK OF THE STATEMENT BY APPLICANT  (I) See eral sheets if necessary)	APPLICANT: Herbert J. NEUHAUS et al. FILING DATE	GROUP & X H
O 1 (t) See real success in necessiary	19 March 2001	0 00

### U.S. PATENT DOCUMENTS

AMINENADE WAR	PATENT NUMBER	ISSUE DATE	PATENTEE	CLASS	SUBCLASS	FILING DATE II APPROPRIATE
NITIAL		06/1974	Evans et al.	339	17 F	
fu	3,818,415	07/1987	Takeda	428	327	
a	4,680,226	02/1989	DiFrancesco	228	115	
m	4,804,132		Su et al.	252	512	
m	4,999,136	03/1991	Tsukagoshi et al.	357	68	
m	5,001,542	03/1991	Difrancesco	228	116	
m	5,083,697	01/1992	Basavanhally et al.	361	406	
The state of the s	5,225,966	07/1993		428	40	
(h)	5,300,340	04/1994	Calhoun et al.	200	262	
Par l	*5,334,809	08/1994	DiFrancesco	361	785	
0	5,430,614	07/1995	Difrancesco	228	104	
a	5,456,404	10/1995	Robinette, Jr. et al.	324	757	
m	*5,471,151	11/1995	DiFrancesco		164	<del> </del>
- 1	*5,494,730	02/1996	Calhoun et al.	428	757	
2	*5,506,514	04/1996	Difrancesco	324	34	
	*5,565,280	10/1996	Difrancesco	429		<del> </del>
M	*5,642,055	06/1997	Difrancesco	324	757	
m	5,670,251	09/1997	Difrancesco	428	325	
<i></i>	5,829,988	11/1998	McMillan et al.	439	70	
	*5,835,359	11/1998	DiFrancesco	361	803	
8	5,841,291	11/1998	Liu et al	324	755	
- P	*5,847,571	12/1998	Liu et al	324	754	_
m	5,880,591	03/1999	Raymond	324	758	
n/		09/1999	Crotzer et al.	174	254	
A.	5,949,029 6,096,982	08/2000	Difrancesco	174	268	

<sup>\*</sup>Cumulative of one or more patents.

# FOREIGN PATENT OR PUBLISHED FOREIGN PATENT APPLICATION

	FOREIGNAN					TRANSLA	ATION
	DOCUMENT NUMBER	PUBLISHED DATE	COUNTRY	CLASS	SUBCLASS	YES	NO
<b> </b>				Ι			

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

Part I' Circuits Assembly, January 1994, Juges 32 55	
Dr. Ken Gilleo, "Evaluating Polymer Free Assembly Solders for Lead – Part I", Circuits Assembly, January 1994, pages 52-56  DATE CONSIDERED 7/3-2/07	
EXAMINER 27 27 27 28 EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance with MPEP 609; Draw line through citation if not in conformance with MPEP 609; Draw line through citation if not in conformance with MPEP 609; Draw line through citation if not in conformance with MPEP 609; Draw line through citation if not in conformance with MPEP 609; Draw line through citation if not in conformance with MPEP 609; Draw line through citation if not in conformance with MPEP 609; Draw line through citation if not in conformance with MPEP 609; Draw line through citation if not in conformance with MPEP 609; Draw line through citation if not in conformance with MPEP 609; Draw line through citation if not in conformance with MPEP 609; Draw line through citation is in conformance with MPEP 609; Draw line through citation is in conformance with MPEP 609; Draw line through citation is in conformance with MPEP 609; Draw line through citation is in conformance with MPEP 609; Draw line through citation is in conformance with MPEP 609; Draw line through citation is in conformance with MPEP 609; Draw line through citation is in conformance with MPEP 609; Draw line through citation is in conformance with MPEP 609; Draw line through citation is in conformance with MPEP 609; Draw line through citation is in conformance with MPEP 609; Draw line through citation is in conformance with MPEP 609; Draw line through citation is in conformance with MPEP 609; Draw line through citation is in conformance with MPEP 609; Draw line through citation is in conformance with MPEP 609; Draw line through citation is in conformance with MPEP 609; Draw line through citation is in conformance with MPEP 609; Draw line through citation is in conformance with MPEP 609; Draw line through citation is in conformance with MPEP 609; Draw line through citation is in conformance with MPEP 609; Draw line through citation with MPEP 609; Draw line through citation with MPEP 609	

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